Regarding the change of names mentioned in the document, such as Hitachi Electric and Hitachi XX, to Renesas Technology Corp.

The semiconductor operations of Mitsubishi Electric and Hitachi were transferred to Renesas Technology Corporation on April 1st 2003. These operations include microcomputer, logic, analog and discrete devices, and memory chips other than DRAMs (flash memory, SRAMs etc.) Accordingly, although Hitachi, Hitachi, Ltd., Hitachi Semiconductors, and other Hitachi brand names are mentioned in the document, these names have in fact all been changed to Renesas Technology Corp. Thank you for your understanding. Except for our corporate trademark, logo and corporate statement, no changes whatsoever have been made to the contents of the document, and these changes do not constitute any alteration to the contents of the document itself.

Renesas Technology Home Page: http://www.renesas.com

Renesas Technology Corp. Customer Support Dept. April 1, 2003



Cautions

Keep safety first in your circuit designs!

Renesas Technology Corporation puts the maximum effort into making semiconductor products better
and more reliable, but there is always the possibility that trouble may occur with them. Trouble with
semiconductors may lead to personal injury, fire or property damage.
Remember to give due consideration to safety when making your circuit designs, with appropriate
measures such as (i) placement of substitutive, auxiliary circuits, (ii) use of nonflammable material or
(iii) prevention against any malfunction or mishap.

Notes regarding these materials

- 1. These materials are intended as a reference to assist our customers in the selection of the Renesas Technology Corporation product best suited to the customer's application; they do not convey any license under any intellectual property rights, or any other rights, belonging to Renesas Technology Corporation or a third party.
- 2. Renesas Technology Corporation assumes no responsibility for any damage, or infringement of any third-party's rights, originating in the use of any product data, diagrams, charts, programs, algorithms, or circuit application examples contained in these materials.
- 3. All information contained in these materials, including product data, diagrams, charts, programs and algorithms represents information on products at the time of publication of these materials, and are subject to change by Renesas Technology Corporation without notice due to product improvements or other reasons. It is therefore recommended that customers contact Renesas Technology Corporation or an authorized Renesas Technology Corporation product distributor for the latest product information before purchasing a product listed herein.
 - The information described here may contain technical inaccuracies or typographical errors. Renesas Technology Corporation assumes no responsibility for any damage, liability, or other loss rising from these inaccuracies or errors.
 - Please also pay attention to information published by Renesas Technology Corporation by various means, including the Renesas Technology Corporation Semiconductor home page (http://www.renesas.com).
- 4. When using any or all of the information contained in these materials, including product data, diagrams, charts, programs, and algorithms, please be sure to evaluate all information as a total system before making a final decision on the applicability of the information and products. Renesas Technology Corporation assumes no responsibility for any damage, liability or other loss resulting from the information contained herein.
- 5. Renesas Technology Corporation semiconductors are not designed or manufactured for use in a device or system that is used under circumstances in which human life is potentially at stake. Please contact Renesas Technology Corporation or an authorized Renesas Technology Corporation product distributor when considering the use of a product contained herein for any specific purposes, such as apparatus or systems for transportation, vehicular, medical, aerospace, nuclear, or undersea repeater use.
- 6. The prior written approval of Renesas Technology Corporation is necessary to reprint or reproduce in whole or in part these materials.
- 7. If these products or technologies are subject to the Japanese export control restrictions, they must be exported under a license from the Japanese government and cannot be imported into a country other than the approved destination.
 - Any diversion or reexport contrary to the export control laws and regulations of Japan and/or the country of destination is prohibited.
- 8. Please contact Renesas Technology Corporation for further details on these materials or the products contained therein.

4M High Speed SRAM (4-Mword \times 1-bit)



ADE-203-1199C (Z)

Rev. 2.0 Feb. 3, 2003

Description

The HM621400HC is a 4-Mbit high speed static RAM organized 4-Mword × 1-bit. It has realized high speed access time by employing CMOS process (6-transistor memory cell)and high speed circuit designing technology. It is most appropriate for the application which requires high speed and high density memory, such as cache and buffer memory in system. The HM621400HC is packaged in 400-mil 32-pin SOJ for high density surface mounting.

Features

• Single 5.0 V supply: $5.0 \text{ V} \pm 10\%$

• Access time: 10/12 ns (max)

• Completely static memory

— No clock or timing strobe required

• Equal access and cycle times

• Directly TTL compatible

— All inputs and outputs

• Operating current: 140/130 mA (max)

• TTL standby current: 40 mA (max)

CMOS standby current: 5 mA (max)

: 1.2 mA (max) (L-version)

• Data retention current: 0.8 mA (max) (L-version)

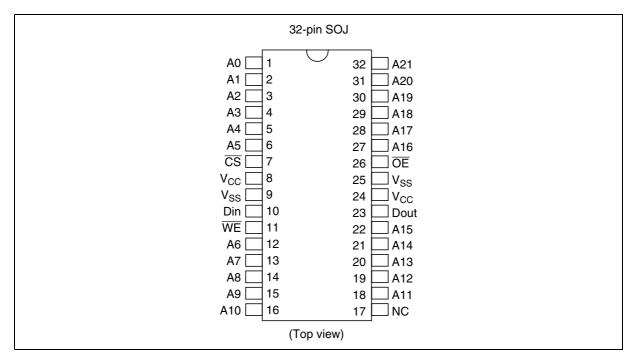
• Data retention voltage: 2 V (min) (L-version)

Center V_{CC} and V_{SS} type pin out

Ordering Information

Type No.	Access time	Device marking	Package
HM621400HCJP-10	10 ns	HM621400CJP10	400-mil 32-pin plastic SOJ (CP-32DB)
HM621400HCJP-12	12 ns	HM621400CJP12	
HM621400HCLJP-10	10 ns	HM621400CLJP10	
HM621400HCLJP-12	12 ns	HM621400CLJP12	

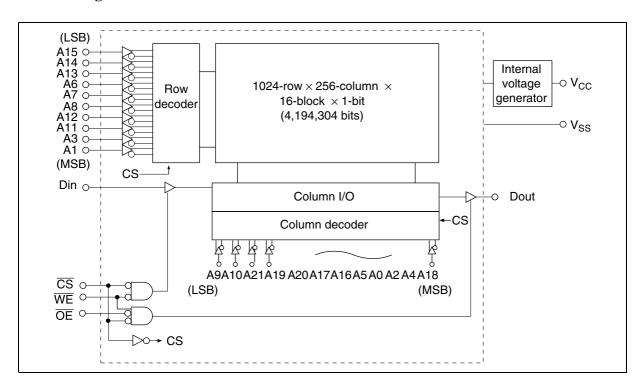
Pin Arrangement



Pin Description

Pin name	Function
A0 to A21	Address input
Din	Data input
Dout	Data output
CS	Chip select
ŌĒ	Output enable
WE	Write enable
V _{cc}	Power supply
V_{ss}	Ground
NC	No connection

Block Diagram



Operation Table

CS	ŌĒ	WE	Mode	V _{cc} current	Dout	Ref. cycle
Н	×	×	Standby	I _{SB} , I _{SB1}	High-Z	_
L	Н	Н	Output disable	I _{cc}	High-Z	_
L	L	Н	Read	I _{cc}	Dout	Read cycle (1) to (3)
L	Н	L	Write	I _{cc}	High-Z	Write cycle (1)
L	L	L	Write	I _{cc}	High-Z	Write cycle (2)

Note: H: V_{H} , L: V_{L} , \times : V_{H} or V_{L}

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit	
Supply voltage relative to V _{ss}	V _{cc}	-0.5 to +7.0	V	
Voltage on any pin relative to V _{ss}	V _T	-0.5^{*1} to $V_{cc}+0.5^{*2}$	V	
Power dissipation	P _T	1.0	W	
Operating temperature	Topr	0 to +70	°C	
Storage temperature	Tstg	−55 to +125	°C	
Storage temperature under bias	Tbias	−10 to +85	°C	

Notes: 1. V_{T} (min) = -2.0 V for pulse width (under shoot) \leq 6 ns.

2. V_T (max) = V_{CC} + 2.0 V for pulse width (over shoot) \leq 6 ns.

Recommended DC Operating Conditions

 $(Ta = 0 \text{ to } +70^{\circ}C)$

Parameter	Symbol	Min	Тур	Max	Unit
Supply voltage	V _{CC} *3	4.5	5.0	5.5	V
	V _{SS} * ⁴	0	0	0	V
Input voltage	V _{IH}	2.2	_	V _{CC} + 0.5*2	V
	V _{IL}	-0.5* ¹	_	0.8	V

Notes: 1. V_{\parallel} (min) = -2.0 V for pulse width (under shoot) \leq 6 ns.

- 2. V_{IH} (max) = V_{CC} + 2.0 V for pulse width (over shoot) \leq 6 ns.
- 3. The supply voltage with all $\rm V_{\rm cc}$ pins must be on the same level.
- 4. The supply voltage with all $V_{\rm ss}$ pins must be on the same level.

DC Characteristics

 $(Ta = 0 \text{ to } +70^{\circ}\text{C}, V_{cc} = 5.0 \text{ V} \pm 10\%, V_{ss} = 0 \text{ V})$

Parameter		Symbol	Min	Typ* ¹	Max	Unit	Test conditions
Input leakage current		II _u I	_	_	2	μΑ	$Vin = V_{ss} to V_{cc}$
Output leakage curre	ent	II _{LO} I	_	_	2	μΑ	$Vin = V_{ss} to V_{cc}$
Operation power supply current	10 ns cycle	I _{cc}		_	140	mA	Min cycle $\overline{CS} = V_{iL}$, lout = 0 mA Other inputs = V_{iH}/V_{iL}
	12 ns cycle	I _{cc}	_	_	130	mA	_
Standby power supply current		l _{SB}	_	_	40	mA	Min cycle, $\overline{CS} = V_{IH}$, Other inputs = V_{IH}/V_{IL}
		I _{SB1}	_	2.5	5	mA	$ f = 0 \text{ MHz} $ $V_{cc} \ge \overline{CS} \ge V_{cc} - 0.2 \text{ V}, $ $(1) 0 \text{ V} \le \text{Vin} \le 0.2 \text{ V or} $ $(2) V_{cc} \ge \text{Vin} \ge V_{cc} - 0.2 \text{ V} $
			*2	0.6*2	1.2*2	_	
Output voltage		V _{oL}	_	_	0.4	V	I _{OL} = 8 mA
		V _{OH}	2.4	_		V	I _{OH} = -4 mA

Notes: 1. Typical values are at $V_{cc} = 5.0 \text{ V}$, $Ta = +25^{\circ}\text{C}$ and not guaranteed.

2. This characteristics is guaranteed only for L-version.

Capacitance

 $(Ta = +25^{\circ}C, f = 1.0 \text{ MHz})$

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions
Input capacitance*1	Cin	_	_	6	pF	Vin = 0 V
	C _{DIN}	_	_	6	pF	V _{DIN} = 0 V
Input/output capacitance*1	C _{DOUT}	_	_	8	pF	$V_{DOUT} = 0 V$

Note: 1. This parameter is sampled and not 100% tested.

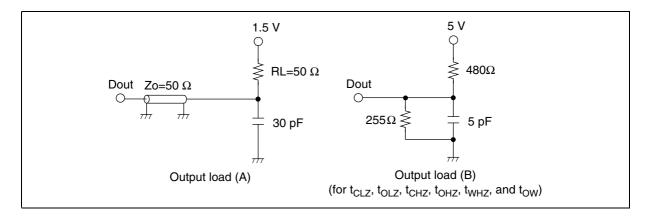
AC Characteristics

(Ta = 0 to +70°C, V_{cc} = 5.0 V ± 10%, unless otherwise noted.)

Test Conditions

Input pulse levels: 3.0 V/0.0 VInput rise and fall time: 3 ns

Input and output timing reference levels: 1.5 V
Output load: See figures (Including scope and jig)



Read Cycle

		TIMOL 1400110					
		-10		-12			
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Read cycle time	t _{rc}	10	_	12	_	ns	
Address access time	t _{AA}	_	10	_	12	ns	
Chip select access time	t _{ACS}	_	10	_	12	ns	
Output enable to output valid	t _{oe}	_	5	_	6	ns	
Output hold from address change	t _{oh}	3	_	3	_	ns	
Chip select to output in low-Z	t _{CLZ}	3	_	3	_	ns	1
Output enable to output in low-Z	t _{olz}	0	_	0	_	ns	1
Chip deselect to output in high-Z	t _{cHZ}	_	5	_	6	ns	1
Output disable to output in high-Z	t _{ohz}	_	5	_	6	ns	1

HM621400HC

Write Cycle

		HM62	1400HC				
		-10		-12			
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Write cycle time	t _{wc}	10	_	12	_	ns	
Address valid to end of write	t _{AW}	7	_	8	_	ns	
Chip select to end of write	t _{cw}	7	_	8	_	ns	9
Write pulse width	t _{wP}	7	_	8	_	ns	8
Address setup time	t _{AS}	0	_	0	_	ns	6
Write recovery time	t _{wR}	0	_	0	_	ns	7
Data to write time overlap	t _{DW}	5	_	6	_	ns	
Data hold from write time	t _{DH}	0	_	0	_	ns	
Write disable to output in low-Z	t _{ow}	3	_	3	_	ns	1
Output disable to output in high-Z	t _{oHZ}	_	5	_	6	ns	1
Write enable to output in high-Z	t _{wHZ}	_	5	_	6	ns	1

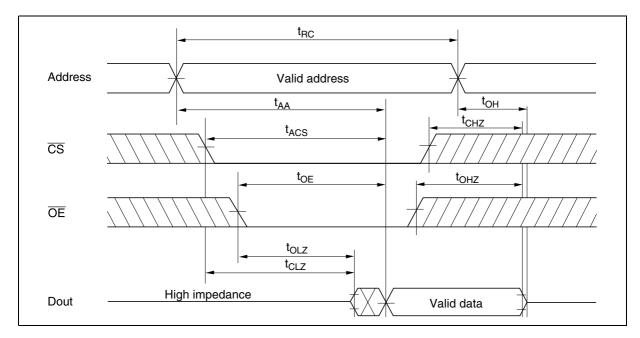
1184004400110

Notes: 1. Transition is measured ±200 mV from steady voltage with output load (B). This parameter is sampled and not 100% tested.

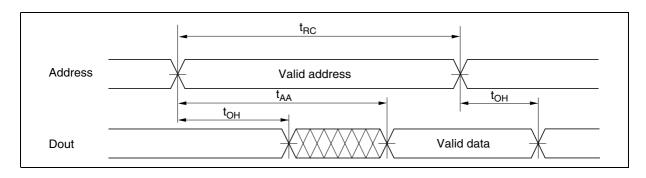
- 2. Address should be valid prior to or coincident with $\overline{\text{CS}}$ transition low.
- 3. WE and/or CS must be high during address transition time.
- 4. If $\overline{\text{CS}}$ and $\overline{\text{OE}}$ are low during this period, Dout pins are in the output state. Then, the data input signals of opposite phase to the outputs must not be applied to them.
- 5. If the $\overline{\text{CS}}$ low transition occurs simultaneously with the $\overline{\text{WE}}$ low transition or after the $\overline{\text{WE}}$ transition, output remains a high impedance state.
- 6. t_{AS} is measured from the latest address transition to the later of \overline{CS} or \overline{WE} going low.
- 7. t_{wB} is measured from the earlier of \overline{CS} or \overline{WE} going high to the first address transition.
- 8. A write occurs during the overlap of a low \overline{CS} and a low \overline{WE} . A write begins at the latest transition among \overline{CS} going low and \overline{WE} going low. A write ends at the earliest transition among \overline{CS} going high and \overline{WE} going high. t_{wp} is measured from the beginning of write to the end of write.
- 9. t_{cw} is measured from the later of \overline{CS} going low to the end of write.

Timing Waveforms

Read Timing Waveform (1) $(\overline{WE} = V_{IH})$

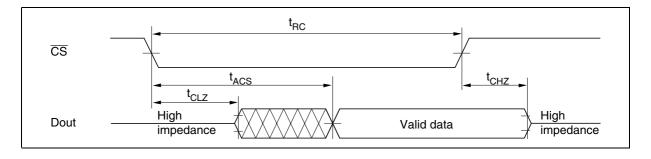


Read Timing Waveform (2) $(\overline{WE} = V_{_{IH}}, \overline{CS} = V_{_{IL}}, \overline{OE} = V_{_{IL}})$

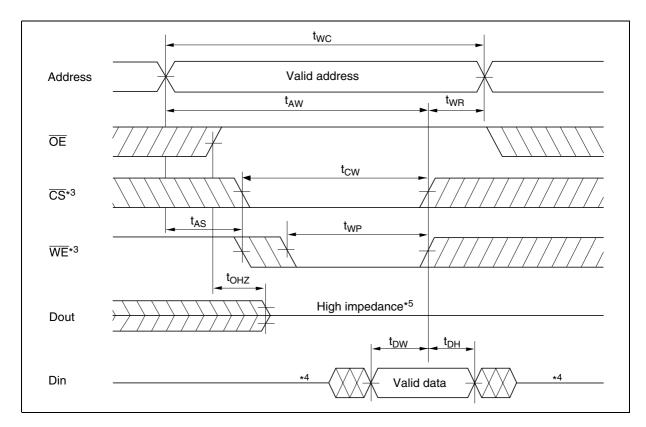


RENESAS

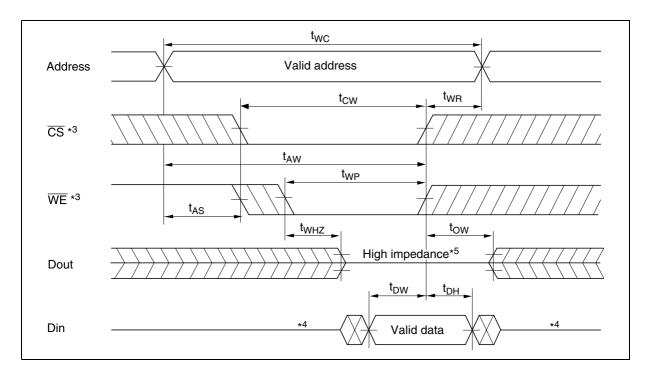
Read Timing Waveform (3) $(\overline{WE} = V_{_{IH}}, \overline{CS} = V_{_{IL}}, \overline{OE} = V_{_{IL}})^{*2}$



Write Timing Waveform (1) $(\overline{WE} \text{ Controlled})$



Write Timing Waveform (2) (CS Controlled)



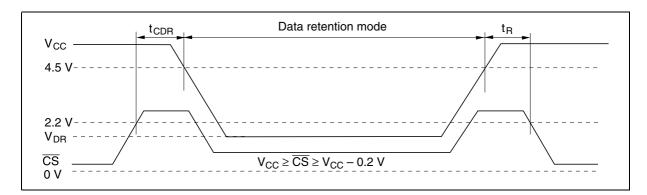
Low $V_{\rm cc}$ Data Retention Characteristics

 $(Ta = 0 \text{ to } +70^{\circ}\text{C})$

This characteristics is guaranteed only for L-version.

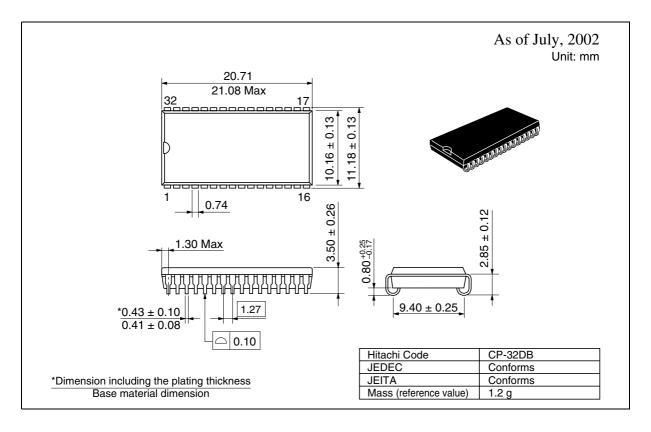
Parameter	Symbol	Min	Тур	Max	Unit	Test conditions
$V_{\rm cc}$ for data retention	$V_{_{ m DR}}$	2.0	_	_	V	$V_{cc} \ge \overline{CS} \ge V_{cc} - 0.2 \text{ V}$ (1) $0 \text{ V} \le \text{Vin} \le 0.2 \text{ V} \text{ or}$ (2) $V_{cc} \ge \text{Vin} \ge V_{cc} - 0.2 \text{ V}$
Data retention current	CCDR		_	800	μА	$V_{cc} = 3 \text{ V}, V_{cc} \ge \overline{\text{CS}} \ge V_{cc} - 0.2 \text{ V}$ (1) $0 \text{ V} \le \text{Vin} \le 0.2 \text{ V} \text{ or}$ (2) $V_{cc} \ge \text{Vin} \ge V_{cc} - 0.2 \text{ V}$
Chip deselect to data retention time	t _{CDR}	0	_	_	ns	See retention waveform
Operation recovery time	t _R	5	_	_	ms	_

Low V_{cc} Data Retention Timing Waveform



Package Dimensions

HM621400HCJP/HCLJP Series (CP-32DB)



Disclaimer

- Hitachi neither warrants nor grants licenses of any rights of Hitachi's or any third party's patent, copyright, trademark, or other intellectual property rights for information contained in this document. Hitachi bears no responsibility for problems that may arise with third party's rights, including intellectual property rights, in connection with use of the information contained in this document.
- 2. Products and product specifications may be subject to change without notice. Confirm that you have received the latest product standards or specifications before final design, purchase or use.
- 3. Hitachi makes every attempt to ensure that its products are of high quality and reliability. However, contact Hitachi's sales office before using the product in an application that demands especially high quality and reliability or where its failure or malfunction may directly threaten human life or cause risk of bodily injury, such as aerospace, aeronautics, nuclear power, combustion control, transportation, traffic, safety equipment or medical equipment for life support.
- 4. Design your application so that the product is used within the ranges guaranteed by Hitachi particularly for maximum rating, operating supply voltage range, heat radiation characteristics, installation conditions and other characteristics. Hitachi bears no responsibility for failure or damage when used beyond the guaranteed ranges. Even within the guaranteed ranges, consider normally foreseeable failure rates or failure modes in semiconductor devices and employ systemic measures such as fail-safes, so that the equipment incorporating Hitachi product does not cause bodily injury, fire or other consequential damage due to operation of the Hitachi product.
- 5. This product is not designed to be radiation resistant.
- 6. No one is permitted to reproduce or duplicate, in any form, the whole or part of this document without written approval from Hitachi.
- 7. Contact Hitachi's sales office for any questions regarding this document or Hitachi semiconductor products.

Sales Offices

ITACHI

Hitachi. Ltd.

Semiconductor & Integrated Circuits Nippon Bldg., 2-6-2, Ohte-machi, Chiyoda-ku, Tokyo 100-0004, Japan Tel: (03) 3270-2111 Fax: (03) 3270-5109

Hitachi Europe Ltd.

HRI http://www.hitachisemiconductor.com/

For further information write to:

Hitachi Semiconductor (America) Inc. 179 East Tasman Drive San Jose CA 95134 Tel: <1> (408) 433-1990 Maidenhead

Electronic Components Group Whitebrook Park Lower Cookham Road Fax: <1>(408) 433-0223 Berkshire SL6 8YA, United Kingdom Fax: <65>-6538-6933/6538-3877 Tel: <44> (1628) 585000 Fax: <44> (1628) 778322

> Hitachi Europe GmbH Electronic Components Group Dornacher Str 3 D-85622 Feldkirchen Postfach 201, D-85619 Feldkirchen Germany

Tel: <49> (89) 9 9180-0 Fax: <49> (89) 9 29 30 00 Hitachi Asia Ltd. Hitachi Tower 16 Collyer Quay #20-00 Singapore 049318 Tel: <65>-6538-6533/6538-8577

URL: http://semiconductor.hitachi.com.sg Tel: <852>-2735-9218

Hitachi Asia Ltd. (Taipei Branch Office) 4/F, No. 167, Tun Hwa North Road Huna-Kuo Buildina Taipei (105), Taiwan Tel: <886>-(2)-2718-3666

Fax: <886>-(2)-2718-8180 Telex: 23222 HAS-TP

URL: http://semiconductor.hitachi.com.tw

Copyright @ Hitachi, Ltd., 2002. All rights reserved. Printed in Japan. Colophon 7.0

Hitachi Asia (Hong Kong) Ltd. Group III (Electronic Components)

7/F., North Tower World Finance Centre Harbour City, Canton Road

Tsim Sha Tsui, Kowloon Hong Kong

Fax: <852>-2730-0281 URL: http://semiconductor.hitachi.com.hk